











SN74LVC2G66 SCES325N - JULY 2001 - REVISED AUGUST 2018

# SN74LVC2G66 Dual Bilateral Analog Switch

#### **Features**

- Available in the Texas Instruments NanoFree™ Package
- 1.65-V to 5.5-V V<sub>CC</sub> Operation
- Inputs Accept Voltages to 5.5 V
- Max  $t_{pd}$  of 0.8 ns at 3.3 V
- High On-Off Output Voltage Ratio
- High Degree of Linearity
- High Speed, Typically 0.5 ns  $(V_{CC} = 3 \text{ V}, C_{L} = 50 \text{ pF})$
- Rail-to-Rail Input/Output
- Low ON-State Resistance, Typically ≉6 Ω  $(V_{CC} = 4.5 \text{ V})$
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II

### Applications

- Wireless Devices
- Audio and Video Signal Routing
- Portable Computing
- Wearable Devices
- Signal Gating, Chopping, Modulation or Demodulation (Modem)
- Signal Multiplexing for Analog-to-Digital and Digital-to-Analog Conversion Systems

## 3 Description

This dual bilateral analog switch is designed for 1.65-V to 5.5-V  $V_{CC}$  operation.

The SN74LVC2G66 device can handle both analog and digital signals. The SN74LVC2G66 device permits signals with amplitudes of up to 5.5 V (peak) to be transmitted in either direction.

NanoFree package technology is breakthrough in IC packaging concepts, using the die as the package.

Each switch section has its own enable-input control (C). A high-level voltage applied to C turns on the associated switch section.

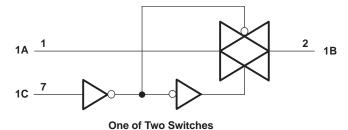
Applications include signal gating, chopping, modulation or demodulation (modem), and signal multiplexing for analog-to-digital and digital-to-analog conversion systems.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN74LVC2G66DCT	SSOP (8)	2.95 mm × 2.80 mm
SN74LVC2G66DCU	VSSOP (8)	2.30 mm × 2.00 mm
SN74LVC2G66YZP	DSBGA (8)	1.91 mm × 0.91 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

## Logic Diagram, Each Switch (Positive Logic)







T۶	ah	Ι۵	Ωf	Co	nte	nts
	ı		v.	$\mathbf{v}$	1116	

2				
_	Applications 1		8.2 Functional Block Diagram	13
3	Description 1		8.3 Feature Description	13
4	Revision History2		8.4 Device Functional Modes	13
5	Pin Configuration and Functions	9	Application and Implementation	14
6	Specifications		9.1 Application Information	14
U	6.1 Absolute Maximum Ratings		9.2 Typical Application	14
	6.2 ESD Ratings	10	Power Supply Recommendations	15
	6.3 Recommended Operating Conditions	11	Layout	16
	6.4 Thermal Information		11.1 Layout Guidelines	16
	6.5 Electrical Characteristics 5		11.2 Layout Example	
	6.6 Switching Characteristics 6	12	Device and Documentation Support	
	6.7 Analog Switch Characteristics		12.1 Community Resources	
	6.8 Operating Characteristics		12.2 Trademarks	
	6.9 Typical Characteristics		12.3 Electrostatic Discharge Caution	
7	• •		12.4 Glossary	
7 8	Parameter Measurement Information 8  Detailed Description	13	Mechanical, Packaging, and Orderable	
R	evision History			
OTE				
_	: Page numbers for previous revisions may differ from	page numb	ers in the current version.	
	•	page numb	pers in the current version.	Page
hanç	: Page numbers for previous revisions may differ from			
hanç	: Page numbers for previous revisions may differ from ges from Revision M (May 2018) to Revision N			
<b>hanç</b> Ch	: Page numbers for previous revisions may differ from ges from Revision M (May 2018) to Revision N			
Ch Ch	: Page numbers for previous revisions may differ from ges from Revision M (May 2018) to Revision N  nanged the YZP pin configuration	M		Page
Ch Ch Chang Up	Page numbers for previous revisions may differ from the sees from Revision M (May 2018) to Revision N panged the YZP pin configuration pages from Revision L (September 2015) to Revision added pinout image and the Pin Function table	M		Page
Ch Ch Chang Ch	: Page numbers for previous revisions may differ from  ges from Revision M (May 2018) to Revision N  hanged the YZP pin configuration	M		Page 3
Ch Ch Chang Ch	Page numbers for previous revisions may differ from the sees from Revision M (May 2018) to Revision N panged the YZP pin configuration pages from Revision L (September 2015) to Revision added pinout image and the Pin Function table	M		Page 3
Chang Chang Ch Ch	: Page numbers for previous revisions may differ from  ges from Revision M (May 2018) to Revision N  hanged the YZP pin configuration	M		Page 3

Typical Characteristics section, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation 

Changes from Revision J (December 2011) to Revision K

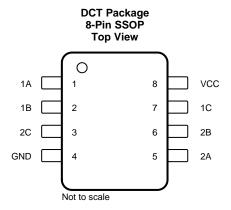
**Page** 

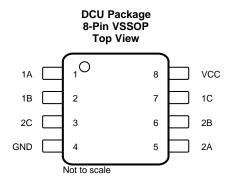
Submit Documentation Feedback

Copyright © 2001-2018, Texas Instruments Incorporated

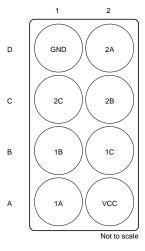


# 5 Pin Configuration and Functions





#### YZP Package 8-Pin DSBGA Bottom View



See mecahnical drawings for dimensions.

## **Pin Functions**

	PIN							
NAME	DCT DCU	YZP	I/O	DESCRIPTION				
1A	1	A1	I/O	Bidirectional signal to be switched				
1B	2	B1	I/O	Bidirectional signal to be switched				
2C	3	C1	I	Controls the switch (L = OFF, H = ON)				
2A	5	D2	I/O	Bidirectional signal to be switched				
2B	6	C2	I/O	Bidirectional signal to be switched				
1C	7	B2	I	Controls the switch (L = OFF, H = ON)				
GND	4	D1	_	Ground pin				
V <sub>CC</sub>	8	A2	_	Power pin				



## 6 Specifications

### 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage <sup>(2)</sup>		-0.5	6.5	V
$V_{I}$	Input voltage (2)(3)		-0.5	6.5	V
Vo	Switch I/O voltage <sup>(2)(3)(4)</sup>		-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Control input clamp current	V <sub>I</sub> < 0		<b>–</b> 50	mA
I <sub>I/OK</sub>	I/O port diode current	$V_{I/O} < 0$ or $V_{I/O} > V_{CC}$		<b>–</b> 50	mA
I <sub>T</sub>	On-state switch current	$V_{I/O} = 0$ to $V_{CC}$		±50	mA
	Continuous current through V <sub>CC</sub> or GND			±100	mA
T <sub>stg</sub>	Storage temperature		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to ground, unless otherwise specified.

## 6.2 ESD Ratings

			VALUE	UNIT
	Floatroatatio	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins (1)	±2000	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	±1000	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

## 6.3 Recommended Operating Conditions

See (1).

			MIN	MAX	UNIT	
V <sub>CC</sub>	Supply voltage		1.65	5.5	V	
V <sub>I/O</sub>	I/O port voltage		0	V <sub>CC</sub>	V	
		V <sub>CC</sub> = 1.65 V to 1.95 V	V <sub>CC</sub> × 0.65			
V <sub>IH</sub> Hiç	High level in a trade of posterior	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	$V_{CC} \times 0.7$		.,	
	High-level input voltage, control input	V <sub>CC</sub> = 3 V to 3.6 V	$V_{CC} \times 0.7$		V	
		V <sub>CC</sub> = 4.5 V to 5.5 V	$V_{CC} \times 0.7$			
		V <sub>CC</sub> = 1.65 V to 1.95 V		V <sub>CC</sub> × 0.35		
	Low-level input voltage, control input	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		$V_{CC} \times 0.3$	V	
$V_{IL}$		Low-level input voltage, control input	Low-level input voltage, control input	V <sub>CC</sub> = 3 V to 3.6 V		$V_{CC} \times 0.3$
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		$V_{CC} \times 0.3$		
VI	Control input voltage		0	5.5	V	
		V <sub>CC</sub> = 1.65 V to 1.95 V		20		
A + / A > .	Input transition rise or fall time	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		20	ns/V	
Δt/Δv	Input transition rise or fall time	V <sub>CC</sub> = 3 V to 3.6 V		10	115/ V	
		V <sub>CC</sub> = 4.5 V to 5.5 V		10		
T <sub>A</sub>	Operating free-air temperature		-40	85	°C	

All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, SCBA004.

<sup>(3)</sup> The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

<sup>(4)</sup> This value is limited to 5.5 V maximum.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



### 6.4 Thermal Information

			SN74LVC2G66				
	THERMAL METRIC <sup>(1)</sup>	DCT (SSOP)	DCU (VSSOP)	YZP (DSBGA)	UNIT		
		8 PINS	8 PINS	8 PINS			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	186.1	204.4	102	°C/W		
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	116.5	77	_	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	98.6	83.2	_	°C/W		
ΨЈТ	Junction-to-top characterization parameter	42.2	7.1	_	°C/W		
ΨЈВ	Junction-to-board characterization parameter	97.6	82.7	_	°C/W		
R <sub>0</sub> JC(bot)	Junction-to-case (bottom) thermal resistance	n/a	n/a	_	°C/W		

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

## 6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITION	ONS	V <sub>CC</sub>	MIN TYP(1)	MAX	UNIT
			$I_S = 4 \text{ mA}$	1.65 V	12.5	30	
_	ON state quitab registence	$V_I = V_{CC}$ or GND,	$I_S = 8 \text{ mA}$	2.3 V	9	20	Ω
r <sub>on</sub>	ON-state switch resistance	V <sub>C</sub> = V <sub>IH</sub> (see Figure 3 and Figure 1)	I <sub>S</sub> = 24 mA	3 V	7.5	15	12
		,	I <sub>S</sub> = 32 mA	4.5 V	6	10	
			$I_S = 4 \text{ mA}$	1.65 V	85	120 <sup>(1)</sup>	
-	Peak ON-state resistance	$V_I = V_{CC}$ to GND,	$I_S = 8 \text{ mA}$	2.3 V	22	30 <sup>(1)</sup>	Ω
r <sub>on(p)</sub>	reak ON-state resistance	V <sub>C</sub> = V <sub>IH</sub> (see Figure 3 and Figure 1)	$I_S = 24 \text{ mA}$	3 V	12	20	12
			$I_S = 32 \text{ mA}$	4.5 V	7.5	15	
			$I_S = 4 \text{ mA}$	1.65 V		7	
۸۰	Difference of ON-state resistance	$V_I = V_{CC}$ to GND, $V_C = V_{IH}$	$I_S = 8 \text{ mA}$	2.3 V		5	Ω
$\Delta r_{on}$	<sup>ΔI</sup> on between switches	(see Figure 3 and Figure 1)	$I_S = 24 \text{ mA}$	3 V		3	12
			$I_S = 32 \text{ mA}$	4.5 V		2	
		$V_I = V_{CC}$ and $V_O = GND$ or				±1	
I <sub>S(off)</sub>	OFF-state switch leakage current	$V_I = GND$ and $V_O = V_{CC}$ , $V_C = V_{IL}$ (see Figure 4)		5.5 V		±0.1 <sup>(1)</sup>	μА
I <sub>S(on)</sub>	ON-state switch leakage current	$V_I = V_{CC}$ or GND, $V_C = V_{IH}$ , $V_C$	= Open	5.5 V		±1	μА
'S(on)	Or state switch leakage current	(see Figure 5)		0.0 V		±0.1 <sup>(1)</sup>	μπ
I <sub>I</sub>	Control input current	$V_C = V_{CC}$ or GND		5.5 V		±1	μА
'1	Control input current	AC = ACC OL QIAD		3.5 V		±0.1 <sup>(1)</sup>	μΛ
I <sub>CC</sub>	Supply current	$V_C = V_{CC}$ or GND		5.5 V		10	μА
icc	Зарру сапен	AC = ACC OL QIAD		3.5 V		1 <sup>(1)</sup>	μΛ
$\Delta I_{CC}$	Supply-current change	$V_C = V_{CC} - 0.6 \text{ V}$		5.5 V		500	μΑ
C <sub>ic</sub>	Control input capacitance			5 V	3.5		pF
C <sub>io(off)</sub>	Switch input / output capacitance			5 V	6		pF
C <sub>io(on)</sub>	Switch input / output capacitance			5 V	14		pF

(1)  $T_A = 25^{\circ}C$ 



## 6.6 Switching Characteristics

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = ± 0.1	1.8 V 5 V	V <sub>CC</sub> = : ± 0.2		V <sub>CC</sub> = ± 0.3		V <sub>CC</sub> = ± 0.5		UNIT
	(INFOI)	(001701)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
$t_{pd}^{(1)}$	A or B	B or A		2		1.2		8.0		0.6	ns
t <sub>en</sub> <sup>(2)</sup>	С	A or B	2.3	10	1.6	5.6	1.5	4.4	1.3	3.9	ns
t <sub>dis</sub> (3)	С	A or B	2.5	10.5	1.2	6.9	2	7.2	1.1	6.3	ns

<sup>(1)</sup> t<sub>PLH</sub> and t<sub>PHL</sub> are the same as t<sub>pd</sub>. The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).

## 6.7 Analog Switch Characteristics

 $T_A = 25^{\circ}C$ 

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	V <sub>CC</sub>	ТҮР	UNIT	
				1.65 V	35		
			$C_L = 50 \text{ pF}, R_L = 600 \Omega,$	2.3 V	120		
			f <sub>in</sub> = sine wave (see Figure 6)	3 V	175		
Frequency response	A or B	B or A		4.5 V	195	MHz	
(switch on)	AUB	BUIA		1.65 V	>300	IVITIZ	
			$C_L = 5 \text{ pF}, R_L = 50 \Omega,$	2.3 V	>300		
			f <sub>in</sub> = sine wave (see Figure 6)	3 V	>300		
				4.5 V	>300		
				1.65 V	-58		
			$C_L = 50 \text{ pF}, R_L = 600 \Omega,$	2.3 V	-58		
Crosstalk <sup>(1)</sup> (between switches)			f <sub>in</sub> = 1 MHz (sine wave) (see Figure 7)	3 V	-58	dB	
	A or B	B or A		4.5 V	-58		
	A OI D	BUIA		1.65 V	-42		
			$C_L = 5 \text{ pF}, R_L = 50 \Omega,$	2.3 V	-42		
			f <sub>in</sub> = 1 MHz (sine wave) (see Figure 7)	3 V	-42		
				4.5 V	-42		
				1.65 V	35		
Crosstalk	С	A or D	$C_L = 50 \text{ pF}, R_L = 600 \Omega,$	2.3 V	50	m\/	
(control input to signal output)	C	Aorb	A or B $f_{in} = 1 \text{ MHz}$	f <sub>in</sub> = 1 MHz (square wave) (see Figure 8)	3 V	70	mV
				4.5 V	100		
				1.65 V	-58		
			$C_L = 50 \text{ pF}, R_L = 600 \Omega,$	2.3 V	-58		
			f <sub>in</sub> = 1 MHz (sine wave) (see Figure 9)	3 V	-58		
Feedthrough attenuation	A D	D A		4.5 V	-58	dB	
(switch off)	A or B	B or A		1.65 V	-42		
			$C_L = 5 \text{ pF}, R_L = 50 \Omega,$	2.3 V	-42		
			f <sub>in</sub> = 1 MHz (sine wave) (see Figure 9)	3 V	-42		
			,	4.5 V	-42		

(1) Adjust fin voltage to obtain 0 dBm at input.

<sup>2)</sup> t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.

<sup>(3)</sup> t<sub>PLZ</sub> and t<sub>PHZ</sub> are the same as t<sub>dis</sub>.



# **Analog Switch Characteristics (continued)**

 $T_A = 25$ °C

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	V <sub>cc</sub>	ТҮР	UNIT
			$C_L$ = 50 pF, $R_L$ = 10 k $\Omega$ , $f_{in}$ = 1 kHz (sine wave) (see Figure 10)	1.65 V	0.1%	
				2.3 V	0.025%	
	A == D	B or A		3 V	0.015%	
Sine-wave distortion				4.5 V	0.01%	
Sille-wave distortion	A or B			1.65 V	0.15%	
			$C_L = 50 \text{ pF}, R_L = 10 \text{ k}\Omega,$ $f_{in} = 10 \text{ kHz (sine wave)}$ (see Figure 10)	2.3 V	0.025%	
				3 V	0.015%	
				4.5 V	0.01%	

## 6.8 Operating Characteristics

 $T_A = 25$ °C

	PARAMETER TEST		V <sub>CC</sub> = 1.8 V	$V_{CC} = 2.5 \text{ V}$	V <sub>CC</sub> = 3.3 V	V <sub>CC</sub> = 5 V	UNIT
PARAMETER		CONDITIONS	TYP	TYP	TYP	TYP	UNIT
$C_{pd}$	Power dissipation capacitance	f = 10 MHz	8	9	9.5	11	pF

# 6.9 Typical Characteristics

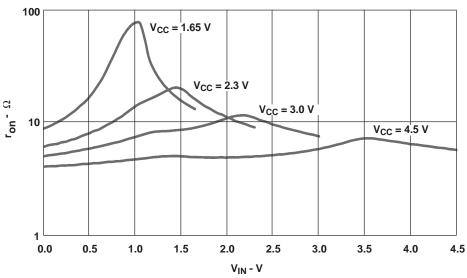
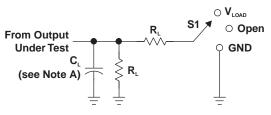


Figure 1. Typical  $r_{on}$  as a Function of Input Voltage (V<sub>I</sub>) for  $V_{I}$  = 0 to  $V_{CC}$ 

Submit Documentation Feedback



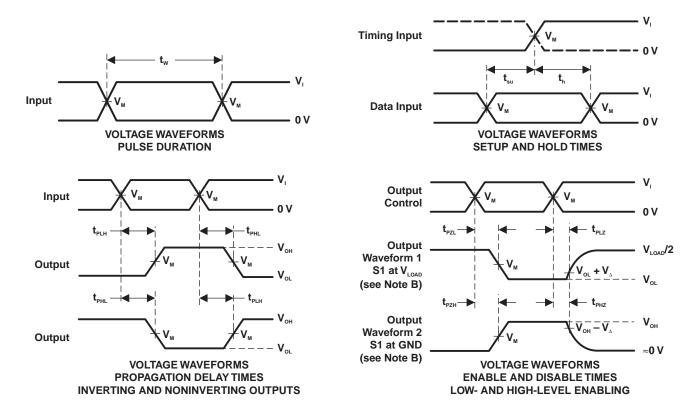
### 7 Parameter Measurement Information



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	V <sub>LOAD</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

ı	0	Λ	n	CI	D		ш	ıT
L	-0	м	u	U	м	•	u	

.,	INF	PUTS	.,	.,			.,
V <sub>cc</sub>	V,	t,/t,	V <sub>M</sub>	V <sub>LOAD</sub>	C <sub>∟</sub>	R <sub>⊾</sub>	V <sub>A</sub>
$1.8~\textrm{V}\pm0.15~\textrm{V}$	V <sub>cc</sub>	≤2 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	30 pF	<b>1 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	V <sub>cc</sub>	≤2 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	30 pF	500 Ω	0.15 V
3.3 V $\pm$ 0.3 V	$V_{cc}$	≤2.5 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	50 pF	<b>500</b> Ω	0.3 V
5 V $\pm$ 0.5 V	V <sub>cc</sub>	≤2.5 ns	V <sub>cc</sub> /2	2 × V <sub>cc</sub>	50 pF	<b>500</b> Ω	0.3 V



NOTES: A. C<sub>∟</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators have the following characteristics: PRR  $\leq$  10 MHz,  $Z_o = 50 \ \Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G.  $t_{\mbox{\tiny PLH}}$  and  $t_{\mbox{\tiny PHL}}$  are the same as  $t_{\mbox{\tiny pd}}$
- H. All parameters and waveforms are not applicable to all devices.

Figure 2. Load Circuit and Voltage Waveforms

Submit Documentation Feedback

Copyright © 2001–2018, Texas Instruments Incorporated



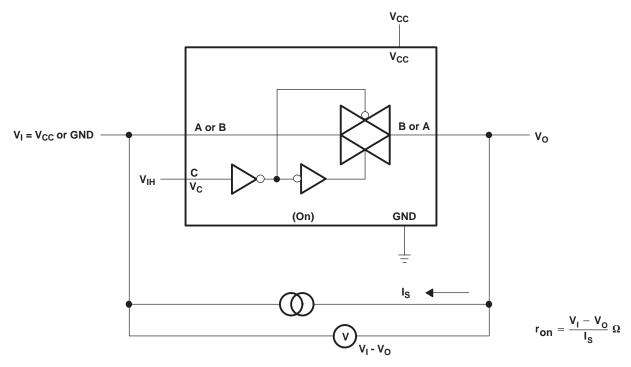


Figure 3. ON-State Resistance Test Circuit

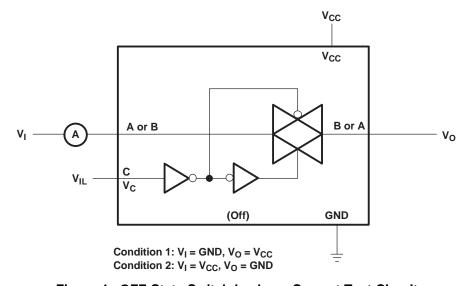


Figure 4. OFF-State Switch Leakage-Current Test Circuit



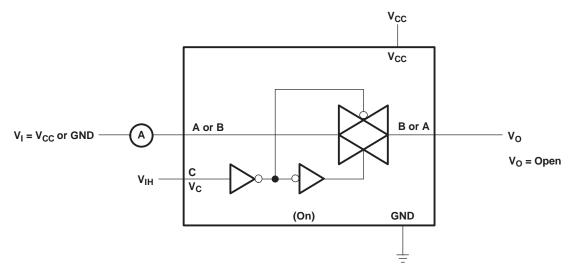


Figure 5. ON-State Leakage-Current Test Circuit

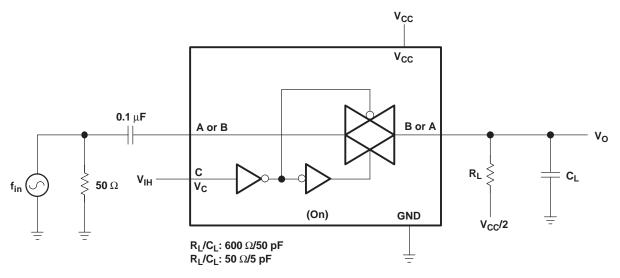


Figure 6. Frequency Response (Switch On)



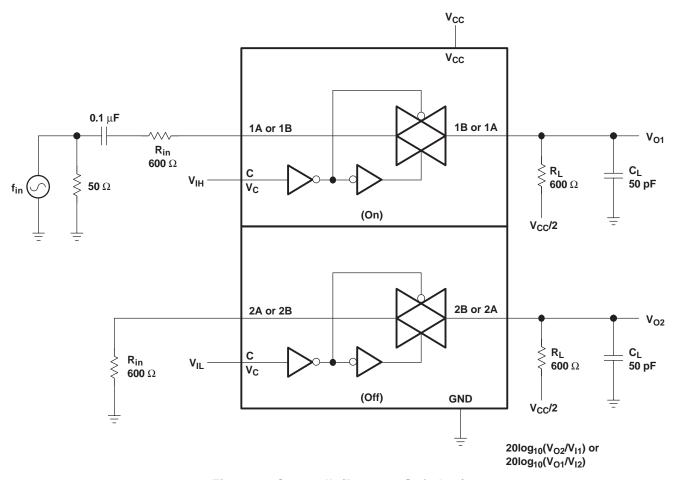


Figure 7. Crosstalk (Between Switches)

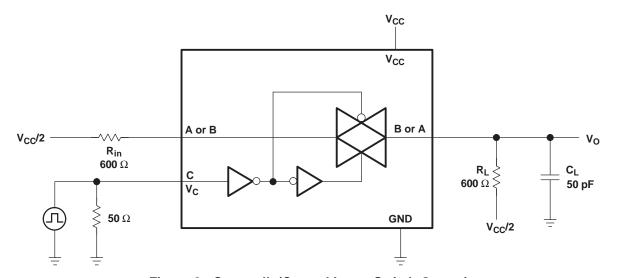


Figure 8. Crosstalk (Control Input, Switch Output)



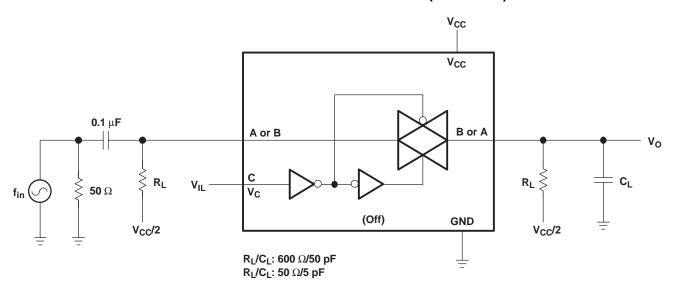


Figure 9. Feedthrough (Switch Off)

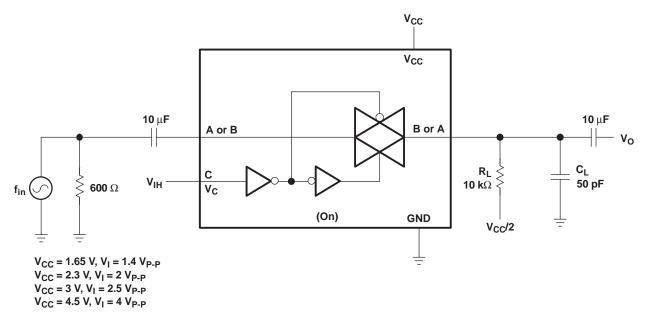


Figure 10. Sine-Wave Distortion

Submit Documentation Feedback



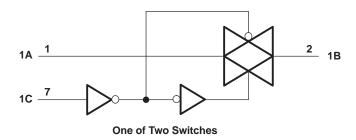
## 8 Detailed Description

#### 8.1 Overview

This dual bilateral analog switch is designed for 1.65-V to 5.5-V  $V_{CC}$  operation. Robust LVC family technology allows this device to accept input voltages without connecting power to  $V_{CC}$ .

The SN74LVC2G66 device permits signals with amplitudes of up to 5.5 V (peak) to be transmitted in either direction. A high-level voltage applied to the control pin C enables the respective switch to begin propagating signals across the device. A low-level voltage disables this transmission. Each device incorporates two switches with independent control and operation.

## 8.2 Functional Block Diagram



### 8.3 Feature Description

Each switch section has its own enable-input control (C). A high-level voltage applied to C turns on the associated switch section. When C is this Signals can pass through A to B or B to A. Low ON-resistance of 6  $\Omega$  at 4.5-V V<sub>CC</sub> is ideal for analog signal conditioning systems. The control signals can accept voltages up to 5.5 V without V<sub>CC</sub> connected in the system. Combination of lower t<sub>pd</sub> of 0.8 ns at 3.3 V and low enable and disable time make this part suitable for high-speed signal switching applications.

### 8.4 Device Functional Modes

Table 1 lists the functional modes of the SN74LVC2G66.

**Table 1. Function Table** 

CONTROL INPUT (C)	SWITCH
L	Off
Н	On



## 9 Application and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

## 9.1 Application Information

The SN74LVC2G66 can be used in any situation where an Dual SPST switch would be used and a solid-state, voltage controlled version is preferred.

## 9.2 Typical Application

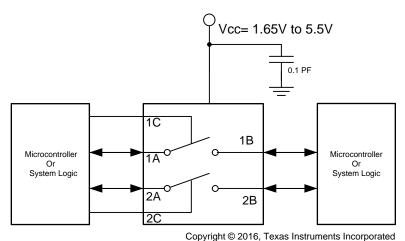


Figure 11. Typical Application Schematic

### 9.2.1 Design Requirements

The SN74LVC2G66 allows on/off control of analog and digital signals with a digital control signal. All input signals should remain between 0 V and  $V_{CC}$  for optimal operation.

#### 9.2.2 Detailed Design Procedure

- 1. Recommended Input Conditions:
  - For rise time and fall time specifications, see  $\Delta t/\Delta v$  in the Recommended Operating Conditions table.
  - For specified high and low levels, see V<sub>IH</sub> and V<sub>IL</sub> in the Recommended Operating Conditions table.
  - Inputs and outputs are overvoltage tolerant allowing them to go as high as 5.5 V at any valid V<sub>CC</sub>.
- 2. Recommended Output Conditions:
  - Load currents should not exceed ±50 mA.
- 3. Frequency Selection Criterion:
  - Maximum frequency tested is 150 MHz.
  - Added trace resistance or capacitance can reduce maximum frequency capability; use layout practices as directed in *Layout*.

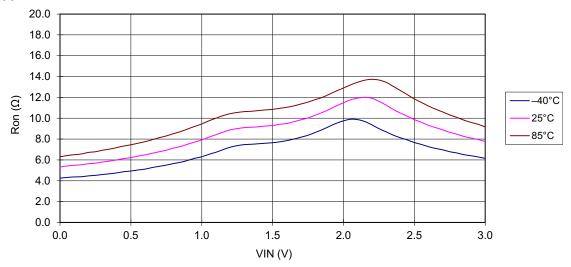
Submit Documentation Feedback

Copyright © 2001–2018, Texas Instruments Incorporated



## **Typical Application (continued)**

#### 9.2.3 Application Curve



Pin: A-B,  $V_{CC} = 3 \text{ V}$ ,  $I_S = 24 \text{ mA}$ 

Figure 12. ron vs VI

## 10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*.

Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1- $\mu F$  bypass capacitor is recommended. If there are multiple pins labeled  $V_{CC}$ , then a 0.01- $\mu F$  or 0.022- $\mu F$  capacitor is recommended for each  $V_{CC}$  because the VCC pins will be tied together internally. For devices with dual-supply pins operating at different voltages, for example  $V_{CC}$  and  $V_{DD}$ , a 0.1- $\mu F$  bypass capacitor is recommended for each supply pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. 0.1- $\mu F$  and 1- $\mu F$  capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

Copyright © 2001–2018, Texas Instruments Incorporated

Product Folder Links: SN74LVC2G66



## 11 Layout

## 11.1 Layout Guidelines

Reflections and matching are closely related to loop antenna theory, but different enough to warrant their own discussion. When a PCB trace turns a corner at a 90° angle, a reflection can occur. This is primarily due to the change of width of the trace. At the apex of the turn, the trace width is increased to 1.414 times its width. This upsets the transmission line characteristics, especially the distributed capacitance and self-inductance of the trace — resulting in the reflection.

#### **NOTE**

Not all PCB traces can be straight, and so they will have to turn corners. Figure 13 shows progressively better techniques of rounding corners. Only the last example maintains constant trace width and minimizes reflections.

## 11.2 Layout Example

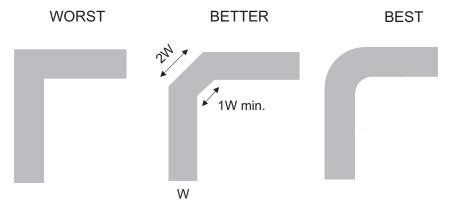


Figure 13. Trace Example

Product Folder Links: SN74LVC2G66

Submit Documentation Feedback



## 12 Device and Documentation Support

### 12.1 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support** *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 12.2 Trademarks

NanoFree, E2E are trademarks of Texas Instruments. All other trademarks are the property of their respective owners.

### 12.3 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

## 12.4 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.





24-Aug-2018

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
SN74LVC2G66DCTR	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	C66 (R, Z)	Samples
SN74LVC2G66DCTRE4	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	C66 (R, Z)	Samples
SN74LVC2G66DCTRG4	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	C66 (R, Z)	Samples
SN74LVC2G66DCUR	ACTIVE	VSSOP	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 85	(66, C66Q, C66R) CZ	Samples
SN74LVC2G66DCURG4	ACTIVE	VSSOP	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	C66R	Samples
SN74LVC2G66DCUT	ACTIVE	VSSOP	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 85	(C66Q, C66R)	Samples
SN74LVC2G66DCUTE4	ACTIVE	VSSOP	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	C66R	Samples
SN74LVC2G66DCUTG4	ACTIVE	VSSOP	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	C66R	Samples
SN74LVC2G66YZPR	ACTIVE	DSBGA	YZP	8	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	(C67, C6N)	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

<sup>(3)</sup> MSL. Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



## PACKAGE OPTION ADDENDUM

24-Aug-2018

- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN74LVC2G66:

Automotive: SN74LVC2G66-Q1

NOTE: Qualified Version Definitions:

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 15-Aug-2018

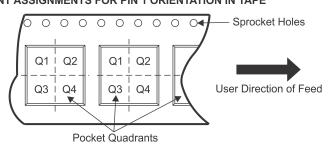
## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LVC2G66DCTR	SM8	DCT	8	3000	180.0	13.0	3.35	4.5	1.55	4.0	12.0	Q3
SN74LVC2G66DCUR	VSSOP	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC2G66DCUR	VSSOP	DCU	8	3000	178.0	9.5	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC2G66DCUR	VSSOP	DCU	8	3000	180.0	9.0	2.05	3.3	1.0	4.0	8.0	Q3
SN74LVC2G66DCURG4	VSSOP	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC2G66DCUTG4	VSSOP	DCU	8	250	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC2G66YZPR	DSBGA	YZP	8	3000	178.0	9.2	1.02	2.02	0.63	4.0	8.0	Q1

www.ti.com 15-Aug-2018



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LVC2G66DCTR	SM8	DCT	8	3000	182.0	182.0	20.0
SN74LVC2G66DCUR	VSSOP	DCU	8	3000	202.0	201.0	28.0
SN74LVC2G66DCUR	VSSOP	DCU	8	3000	202.0	201.0	28.0
SN74LVC2G66DCUR	VSSOP	DCU	8	3000	182.0	182.0	20.0
SN74LVC2G66DCURG4	VSSOP	DCU	8	3000	202.0	201.0	28.0
SN74LVC2G66DCUTG4	VSSOP	DCU	8	250	202.0	201.0	28.0
SN74LVC2G66YZPR	DSBGA	YZP	8	3000	220.0	220.0	35.0

## DCT (R-PDSO-G8)

### PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion
- D. Falls within JEDEC MO-187 variation DA.

# DCT (R-PDSO-G8)

## PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





DIE SIZE BALL GRID ARRAY



### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SNVA009 (www.ti.com/lit/snva009).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



# DCU (R-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE (DIE DOWN)



NOTES:

- A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
  - D. Falls within JEDEC MO-187 variation CA.



DCU (S-PDSO-G8)

PLASTIC SMALL OUTLINE PACKAGE (DIE DOWN)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



#### **IMPORTANT NOTICE**

Texas Instruments Incorporated (TI) reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete.

TI's published terms of sale for semiconductor products (http://www.ti.com/sc/docs/stdterms.htm) apply to the sale of packaged integrated circuit products that TI has qualified and released to market. Additional terms may apply to the use or sale of other types of TI products and services.

Reproduction of significant portions of TI information in TI data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such reproduced documentation. Information of third parties may be subject to additional restrictions. Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyers and others who are developing systems that incorporate TI products (collectively, "Designers") understand and agree that Designers remain responsible for using their independent analysis, evaluation and judgment in designing their applications and that Designers have full and exclusive responsibility to assure the safety of Designers' applications and compliance of their applications (and of all TI products used in or for Designers' applications) with all applicable regulations, laws and other applicable requirements. Designer represents that, with respect to their applications, Designer has all the necessary expertise to create and implement safeguards that (1) anticipate dangerous consequences of failures, (2) monitor failures and their consequences, and (3) lessen the likelihood of failures that might cause harm and take appropriate actions. Designer agrees that prior to using or distributing any applications that include TI products, Designer will thoroughly test such applications and the functionality of such TI products as used in such applications.

TI's provision of technical, application or other design advice, quality characterization, reliability data or other services or information, including, but not limited to, reference designs and materials relating to evaluation modules, (collectively, "TI Resources") are intended to assist designers who are developing applications that incorporate TI products; by downloading, accessing or using TI Resources in any way, Designer (individually or, if Designer is acting on behalf of a company, Designer's company) agrees to use any particular TI Resource solely for this purpose and subject to the terms of this Notice.

TI's provision of TI Resources does not expand or otherwise alter TI's applicable published warranties or warranty disclaimers for TI products, and no additional obligations or liabilities arise from TI providing such TI Resources. TI reserves the right to make corrections, enhancements, improvements and other changes to its TI Resources. TI has not conducted any testing other than that specifically described in the published documentation for a particular TI Resource.

Designer is authorized to use, copy and modify any individual TI Resource only in connection with the development of applications that include the TI product(s) identified in such TI Resource. NO OTHER LICENSE, EXPRESS OR IMPLIED, BY ESTOPPEL OR OTHERWISE TO ANY OTHER TI INTELLECTUAL PROPERTY RIGHT, AND NO LICENSE TO ANY TECHNOLOGY OR INTELLECTUAL PROPERTY RIGHT OF TI OR ANY THIRD PARTY IS GRANTED HEREIN, including but not limited to any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information regarding or referencing third-party products or services does not constitute a license to use such products or services, or a warranty or endorsement thereof. Use of TI Resources may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

TI RESOURCES ARE PROVIDED "AS IS" AND WITH ALL FAULTS. TI DISCLAIMS ALL OTHER WARRANTIES OR REPRESENTATIONS, EXPRESS OR IMPLIED, REGARDING RESOURCES OR USE THEREOF, INCLUDING BUT NOT LIMITED TO ACCURACY OR COMPLETENESS, TITLE, ANY EPIDEMIC FAILURE WARRANTY AND ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, AND NON-INFRINGEMENT OF ANY THIRD PARTY INTELLECTUAL PROPERTY RIGHTS. TI SHALL NOT BE LIABLE FOR AND SHALL NOT DEFEND OR INDEMNIFY DESIGNER AGAINST ANY CLAIM, INCLUDING BUT NOT LIMITED TO ANY INFRINGEMENT CLAIM THAT RELATES TO OR IS BASED ON ANY COMBINATION OF PRODUCTS EVEN IF DESCRIBED IN TI RESOURCES OR OTHERWISE. IN NO EVENT SHALL TI BE LIABLE FOR ANY ACTUAL, DIRECT, SPECIAL, COLLATERAL, INDIRECT, PUNITIVE, INCIDENTAL, CONSEQUENTIAL OR EXEMPLARY DAMAGES IN CONNECTION WITH OR ARISING OUT OF TI RESOURCES OR USE THEREOF, AND REGARDLESS OF WHETHER TI HAS BEEN ADVISED OF THE POSSIBILITY OF SUCH DAMAGES.

Unless TI has explicitly designated an individual product as meeting the requirements of a particular industry standard (e.g., ISO/TS 16949 and ISO 26262), TI is not responsible for any failure to meet such industry standard requirements.

Where TI specifically promotes products as facilitating functional safety or as compliant with industry functional safety standards, such products are intended to help enable customers to design and create their own applications that meet applicable functional safety standards and requirements. Using products in an application does not by itself establish any safety features in the application. Designers must ensure compliance with safety-related requirements and standards applicable to their applications. Designer may not use any TI products in life-critical medical equipment unless authorized officers of the parties have executed a special contract specifically governing such use. Life-critical medical equipment is medical equipment where failure of such equipment would cause serious bodily injury or death (e.g., life support, pacemakers, defibrillators, heart pumps, neurostimulators, and implantables). Such equipment includes, without limitation, all medical devices identified by the U.S. Food and Drug Administration as Class III devices and equivalent classifications outside the U.S.

TI may expressly designate certain products as completing a particular qualification (e.g., Q100, Military Grade, or Enhanced Product). Designers agree that it has the necessary expertise to select the product with the appropriate qualification designation for their applications and that proper product selection is at Designers' own risk. Designers are solely responsible for compliance with all legal and regulatory requirements in connection with such selection.

Designer will fully indemnify TI and its representatives against any damages, costs, losses, and/or liabilities arising out of Designer's non-compliance with the terms and provisions of this Notice.